## Notice of References Cited Application/Control No. 10/577,225 Examiner KEZHEN SHEN Applicant(s)/Patent Under Reexamination KATATA ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,108,291 A	08-2000	Ono et al.	369/47.11
*	В	US-6,263,152 B1	07-2001	Hisatomi et al.	386/243
*	С	US-2003/0059205 A1	03-2003	Suzuki, Ryoichi	386/94
*	D	US-2003/0137909 A1	07-2003	Ito et al.	369/47.14
*	Е	US-2003/0179669 A1	09-2003	Takahashi et al.	369/47.14
*	F	US-2003/0193859 A1	10-2003	Mitsuda et al.	369/47.13
*	G	US-2004/0042370 A1	03-2004	Sugimura et al.	369/059.25
*	Ι	US-7,031,239 B2	04-2006	Takahashi et al.	369/47.14
*	I	US-2006/0171281 A1	08-2006	Takahashi et al.	369/053.17
*	J	US-2006/0171282 A1	08-2006	Takahashi et al.	369/053.17
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	Ø					
	R					
	S					
	Т					_

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	٧					
	w					
	х					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.